

# INDEX TO VOLUME 7

## Author Index

- AGER, D.J. *Paper on* 'A light-sensitive marginal-voltage technique for the location of defects in digital micro-circuits', 66-69
- ARMSTRONG, W. *Paper on* 'A program to aid in the design of control charts for variables', 47-48  
*Paper on* 'The GLIM statistical system in quality and reliability', 97-100
- AURASMAA, H. *Paper on* 'Quality control by micro-computers in the paper industry in Finland', 101-5
- BAKER, G.J. *Paper on* 'Quality assurance in engineering design', 33-35
- BONISZEWSKI, T. *Paper on* 'Quality principles of the manufacturing process of flux-covered welding electrodes', 8-9; *Author's reply*, 45
- BOSWELL, D. *Paper on* 'Collection of reliability data on electronic components', 36-37
- BUZZARD, R. *Paper on* 'Reliability growth planning for complex systems', 61-65.
- CAPLEN, R. *Paper on* 'Using the Weibull distribution to predict the reliability of parts when only small samples are available', 16-23
- COLEGATE, B.M. *Paper on* 'Microcomputers and statistics in the prevention of defects', 111-12, 115
- CORNWELL, G.F. *Paper on* 'A light-sensitive marginal-voltage technique for the location of defects in digital microcircuits', 66-69
- CROMBE, R.C. *Paper on* 'Industrial process control instrumentation system's reliability assurance program, reliability growth and field results', 55-58
- DAY, B. *Paper on* 'Attribute sampling plans and O.C. curves for small lots using computer-derived hypergeometric probabilities', 49-52
- DEVEREUX, I.F. *Paper on* 'Reliability growth planning for complex systems', 61-65
- DURRANT, N.F. *Paper on* 'Some case studies in acceptance sampling by attributes', 31-32
- GRAY, C.G. *Paper on* 'Reliability growth planning for complex systems', 61-65
- GUEST, R. *Paper on* 'Gauging: the next five years', 113-15
- HAYES, P. *Paper on* 'Quality assurance and the introduction of a company management information system', 3-7
- HESLOP S. *Paper on* 'Practical experience in implementing quality assurance in a small business', 10-14
- HUTCHINS, D.C. *Paper on* 'The application of the quality circle concept to reliability engineering', 59-60
- JARRETT, R.E. *Paper on* 'Quality principles of the manufacturing process of flux-covered welding electrodes', 8-9; *Author's reply* 45
- LEE-FRAMPTON, J. *Paper on* 'X-rays probe for safety and quality', 38-42
- LEWIS, C.D. *Paper on* 'Cumulative scores: a new concept in the use of cumulative-sum techniques to detect small shifts in process means', 91-96
- MERRILL, R.A. *Paper on* 'Industrial process control instrumentation system's reliability assurance program, reliability growth and field results', 55-58
- NICHOLSON, S. *Discussion on* 'Quality principles of the manufacturing process of flux-covered welding electrodes', 45
- RZEWSKI, G. *Paper on* 'Recent advances in software reliability methods', 80-87
- SMITH, F.J. *Paper on* 'Attribute sampling: a Bayesian approach to rejection conditions', 15
- STEPHENS, C.E. *Paper on* 'A light-sensitive marginal-voltage technique for the location of defects in digital microcircuits', 66-69
- TRUSCOTT, W.T. *Paper on* 'Developments in inspection applied to consumer products', 106-10
- WALLEY, D.M. *Paper on* 'Reliability monitoring of the prototype Advanced Passenger Train', 70-79
- WHITTINGHAM, P.R.B. *Paper on* 'Simplified process controls based on acceptance sampling by attributes', 43-45
- WOOD, D.F. *Paper on* 'An introduction to software', 24-26

## Subject Index

Acceptance sampling by attributes, 31, 43  
Advanced Passenger Train (APT), 70  
Altim microcomputer, 105  
Attribute sampling, 15, 31, 43, 49  
Average Outgoing Quality Limit (AOQL), 50  
Average Run Lengths (ARLs), 91

Bayesian approach, 15  
Bayes's Theorem, 31  
Binomial distribution, 15  
British Standards Institution, 36

Car components, 19  
Certified Test Records, 36  
Clothing industry, inspection, 106

Colour-control techniques, 101  
Colour matching, 109  
Colour monitoring, 101, 109  
Computer-aided design (CAD), 7  
Computer-aided manufacture (CAM), 7  
Computer programs, 50  
Computers  
    glossary of terms, 25  
    *see also* Microcomputers; Software  
Confidence limits, 21  
Control charts, 44  
    design program, 47  
Cumulative scores, 91

Data analysis, 55

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## Author Index

- AGER, D.J. *Paper on* 'A light-sensitive marginal-voltage technique for the location of defects in digital micro-circuits', 66-69
- ARMSTRONG, W. *Paper on* 'A program to aid in the design of control charts for variables', 47-48  
*Paper on* 'The GLIM statistical system in quality and reliability', 97-100
- AURASMAA, H. *Paper on* 'Quality control by micro-computers in the paper industry in Finland', 101-5
- BAKER, G.J. *Paper on* 'Quality assurance in engineering design', 33-35
- BONISZEWSKI, T. *Paper on* 'Quality principles of the manufacturing process of flux-covered welding electrodes', 8-9; *Author's reply*, 45
- BOSWELL, D. *Paper on* 'Collection of reliability data on electronic components', 36-37
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- COLEGATE, B.M. *Paper on* 'Microcomputers and statistics in the prevention of defects', 111-12, 115
- CORNWELL, G.F. *Paper on* 'A light-sensitive marginal-voltage technique for the location of defects in digital microcircuits', 66-69
- CROMBE, R.C. *Paper on* 'Industrial process control instrumentation system's reliability assurance program, reliability growth and field results', 55-58
- DAY, B. *Paper on* 'Attribute sampling plans and O.C. curves for small lots using computer-derived hypergeometric probabilities', 49-52
- DEVEREUX, I.F. *Paper on* 'Reliability growth planning for complex systems', 61-65
- DURRANT, N.F. *Paper on* 'Some case studies in acceptance sampling by attributes', 31-32
- GRAY, C.G. *Paper on* 'Reliability growth planning for complex systems', 61-65
- GUEST, R. *Paper on* 'Gauging: the next five years', 113-15
- HAYES, P. *Paper on* 'Quality assurance and the introduction of a company management information system', 3-7
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- MERRILL, R.A. *Paper on* 'Industrial process control instrumentation system's reliability assurance program, reliability growth and field results', 55-58
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- WALLEY, D.M. *Paper on* 'Reliability monitoring of the prototype Advanced Passenger Train', 70-79
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Altim microcomputer, 105  
Attribute sampling, 15, 31, 43, 49  
Average Outgoing Quality Limit (AOQL), 50  
Average Run Lengths (ARLs), 91

Bayesian approach, 15  
Bayes's Theorem, 31  
Binomial distribution, 15  
British Standards Institution, 36

Car components, 19  
Certified Test Records, 36  
Clothing industry, inspection, 106

Colour-control techniques, 101  
Colour matching, 109  
Colour monitoring, 101, 109  
Computer-aided design (CAD), 7  
Computer-aided manufacture (CAM), 7  
Computer programs, 50  
Computers  
    glossary of terms, 25  
    *see also* Microcomputers; Software  
Confidence limits, 21  
Control charts, 44  
    design program, 47  
Cumulative scores, 91

Data analysis, 55

- Data-base management systems, 6
- Data manipulation, gauging, 114
- Data reduction, 55
- Defect location in digital microcircuits, 66
- Defect prevention by microcomputers and statistics, 111
- Design, engineering, 33
- Design department, 33
- Digital microcircuits, defect location, 66
- Dudding and Jennett scheme, 91
- Electronic components, reliability, 36
- Electronic equipment, failures, 98
- Electronics, gauging equipment, 113
- Engineering design, 33
- Engineering industry, 33
- Failure mechanism, 19
- Failure rate, 19
- Failures, electronic equipment, 98
- Fibre optics, 107
- Finland, paper industry, 101
- Flyover arm, 19
- Garment examination, 108
- Gauging, 113
  - and production technology, 114
  - data manipulation, 114
  - flexibility degree, 114
  - in-process, 113
  - metal-cutting, 111
- Glass manufacture, 18
- GLIM (Generalized Linear Interactive Modelling) system, 97
- Homogenization, 8, 9, 45
- Hypergeometric distribution, 15, 49
- Hypergeometric probabilities, 49
- Information
  - and data, 5
  - and dimension, 5
  - and system requirements, 5
- Information handling, 5
- Information system
  - and processing model, 5
  - automated, 6
  - company management, 3
  - design and specification, 6
- Inspection
  - clothing industry, 106
  - consumer products, 106
- Inspection machines, 107, 109
- Inspection work stations, 108
- Inspector performance, 106
- Inspector selection, 106
- Inspector training, 107
- Instrumentation, 55
- Intracon industrial vision scanner, 107
- Japan, quality circles, 59
- Laser-based inspection, 109
- Limited Poisson distribution, 15
- Manufacturing process, 3, 111
  - welding electrodes, 8, 45
- Marginal voltage technique, 66
- Mean-time-between failures (MTBF), 55-58
- Metal-cutting in manufacturing process, 111
- Metrology, 13
- Microcomputers
  - Altim, 105
  - defects prevention by, 111
  - quality control by, 101
  - SAM, 112
- NAC eye mark camera, 107
- Non-destructive testing, 38
- One-sided control schemes, 93
- Paper industry, Finland, 101
- Poisson distribution, 15, 99
- PROBIT transformation, 99
- Process classifications, 43
- Process controls, 43, 55
- Process metallurgy, 8
- Production technology
  - advances in, 113
  - and gauging, 114
- Quality assurance
  - advantages, 4
  - and good manufacturing practices, 3
  - disadvantages, 4
  - in engineering design, 33
  - in small business, 10
  - justification, 4
  - need for, 13
  - supplier, 13
  - system approach, 3
- Quality circles, Japanese approach, 59
- Quality control by microcomputers, 101
- Quality department, 4, 11
- Quality function, 4
- Quality manual, 11, 12
- Radiation safety, 38
- Records, 3, 7
- Rejection conditions in attribute sampling, 15
- Reliability
  - electronic components, 36
  - prediction when only small samples are available, 16
  - process control instrumentation, 55
  - software, 80
- Reliability analysis, 73
- Reliability engineering, quality circles, 59
- Reliability growth
  - and project development, 61
  - factors affecting, 61
  - practical guidelines for, 62
  - planning, 61, 62
  - prediction, 73
- Reliability monitoring, Advanced Passenger Train, 70
- Safety, X-ray equipment, 38
- SAM microcomputer, 112
- Sample size effects, 44
- Shewhart scheme, 91, 93, 94
- Small business, implementing quality assurance in, 10
- Software, 24
  - checking for correctness, 83
  - complexity, 85, 86
  - definition, 24
  - development and maintenance, 85
  - error detection, 80, 81
  - failure, 80, 81
    - and repair data, 85
  - failure modes, 83
  - faults, 80, 83
  - module complexity, 85
  - reliability methods, 80
  - specification, 83
  - storage, 24
  - testing and fault repair, 83
  - validation, 86
  - versus hardware reliability, 81
- Standards, 8, 10, 13, 45
- Statistical package, GLIM, 97
- Statistics, defects prevention by, 111

Steel quality, 8  
Steel rolling, GLIM analysis, 98  
Steelmaking, 8  
    GLIM analysis, 97  
Supplier quality assurance, 13  
System approach, 3  
System definition, 3  
System development, 3  
  
Taylor MOD III system, 55  
Two-sided control schemes, 91  
  
Video analysis of scan paths, 108

Video equipment, 107  
  
Weibull distribution, 16, 99  
Weibull probability paper, 16  
Welding electrodes  
    flux-covered, 8, 45  
    manufacturing process, 8, 45  
Wood industry, 101  
  
X-ray equipment, 38  
X-ray systems, 38  
X-ray tubes, 38  
    suspension system, 40

## **20th International Quality Assurance Conference New College, Oxford, 30th September and 1st October 1982**

### ***Call for papers***

The theme of this conference will be 'Improving quality: the professional approach'. The following is a non-exclusive list of topics on which papers are requested.

The needs of industry for trained QA personnel  
The roles of universities, polytechnics, and colleges in meeting industrial demands  
The emphasis on QA in science and technological syllabuses  
The national and international trends in QA management and technology  
Subjects in which QA personnel need information:  
    New legislation  
    Commercial implications  
    National and international certification schemes  
    Accreditation systems  
    The impact of computer technology on QA  
    Fast, non-contact methods of measurement  
    Automated inspection and test  
    N.d.t. developments  
    Traceability, recording, and feedback of data

QA in developing industries:  
    Offshore installations and pipelines  
    Microelectronics  
    Nuclear engineering  
    Robotics

Corporate policies for QA  
    Commercial strategy  
    Practical management for quality

Papers from areas outside this list will also be welcomed.

Synopses of not more than 250 words are invited. They should be sent to:

The Conference Secretary, Institute of Quality Assurance  
54 Princes Gate, Exhibition Road, London SW7 2PG.

as soon as possible and not later than 30th January. Papers, the synopses of which have been accepted, will be required in their final form by 30th June so that they can be published in time for the Conference.

